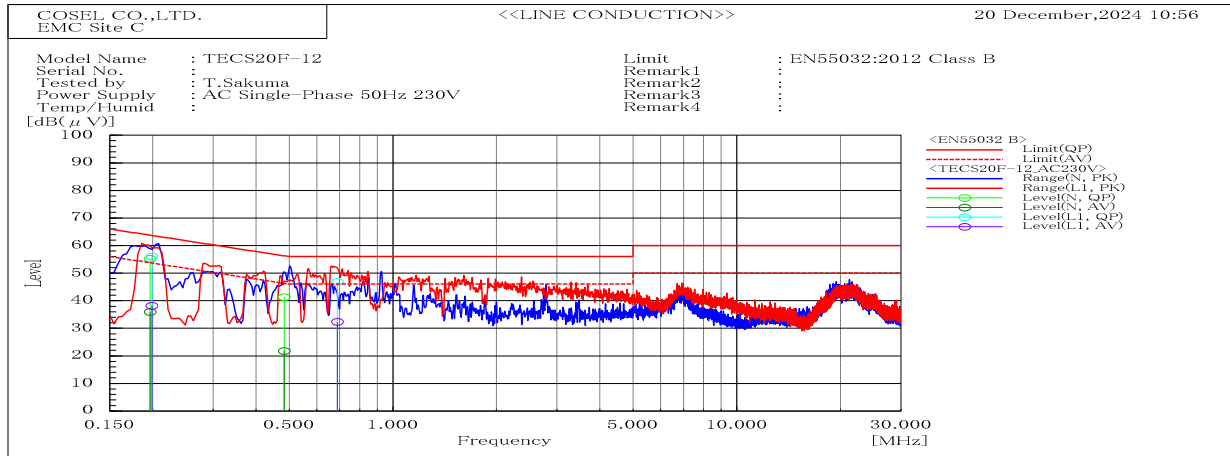
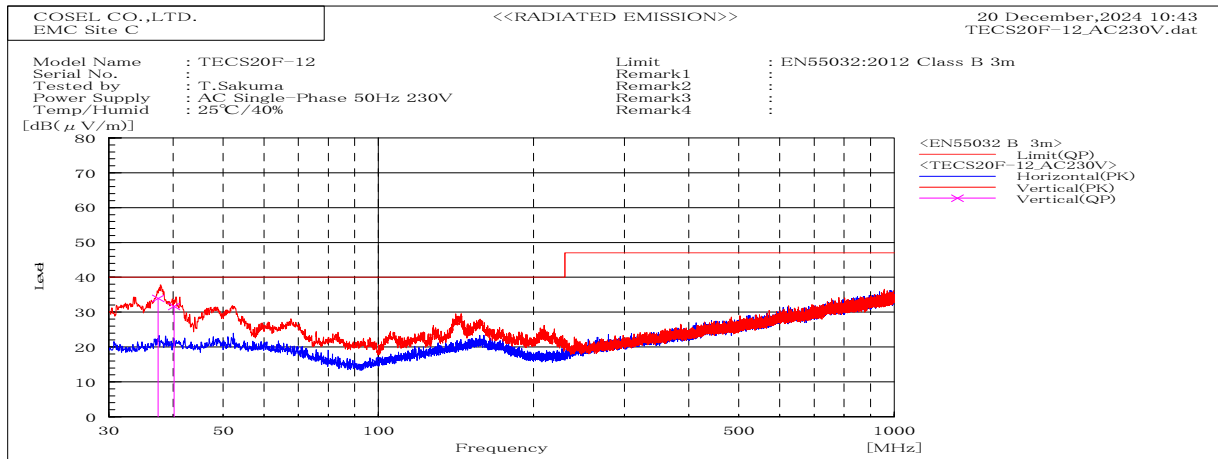


DATA SHEET		Date	24-Mar-25
Model	TECS20F-12	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sakuma



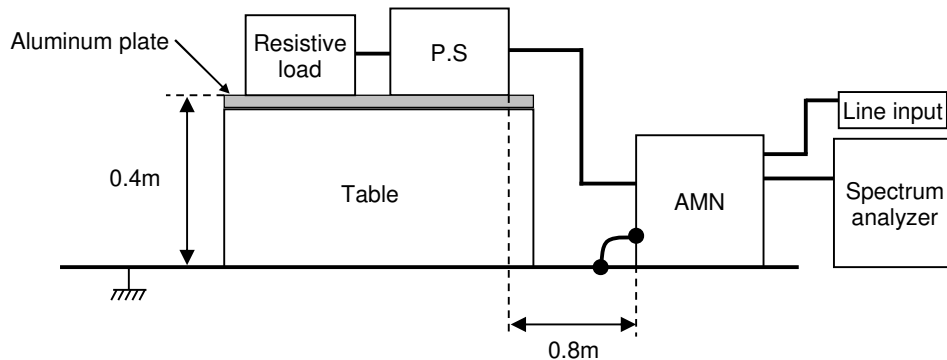
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.199	L1	56.1	38.2	63.7	53.7	7.6	15.5	Pass	
0.689	L1	46.9	32.3	56	46	9.1	13.7	Pass	
0.197	N	55.2	35.9	63.7	53.7	8.5	17.8	Pass	
0.482	N	41.3	21.7	56.3	46.3	15	24.6	Pass	



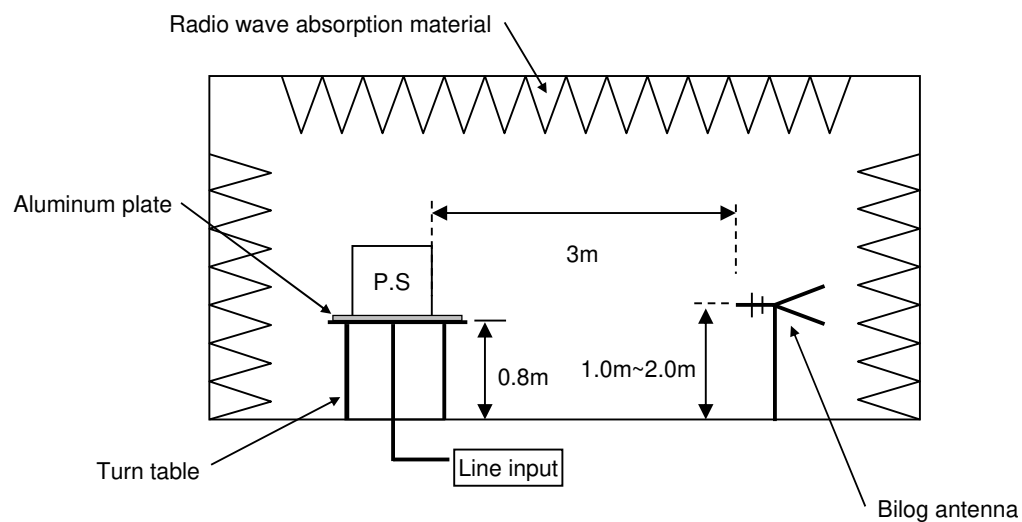
Frequency	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height	Angle	Remark
MHz			dB( $\mu$ V/m)	dB( $\mu$ V/m)	dB				
			QP	QP	QP		cm	deg	
37.404	V	Stable	33.9	40	6.1	Pass	101.6	329.5	
40.174	V	Stable	31.6	40	8.4	Pass	100	119	

DATA SHEET		Date	24-Mar-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Sakuma

### 1. Line conduction



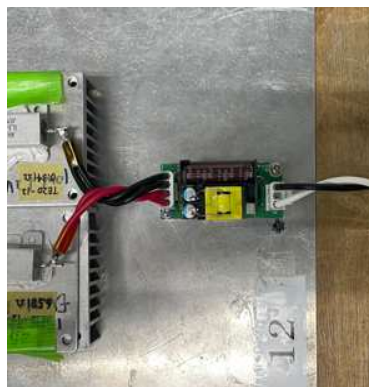
### 2. Radiated emission



## Conditions

Test : EMI  
Model Name : TECS20F-12

### 1.LINE CONDUCTION



### 2.RADIATED EMISSION

